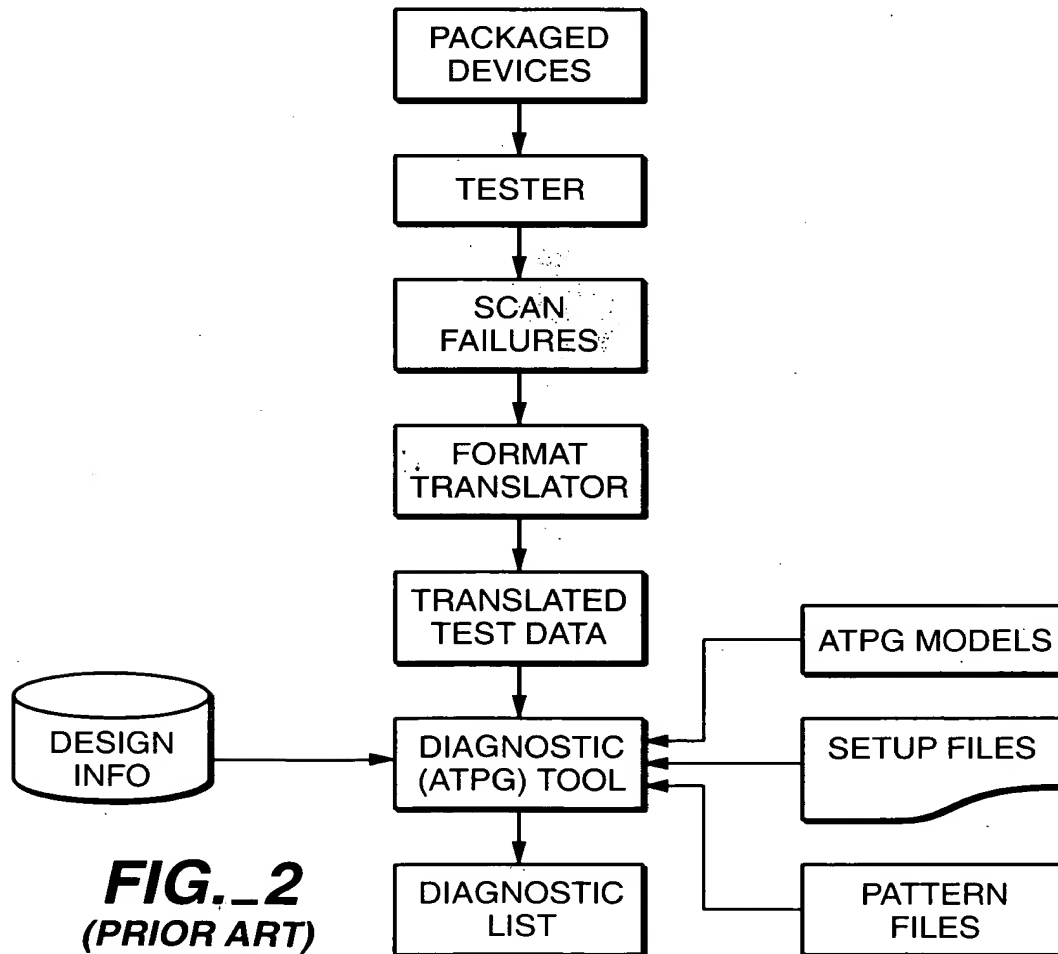
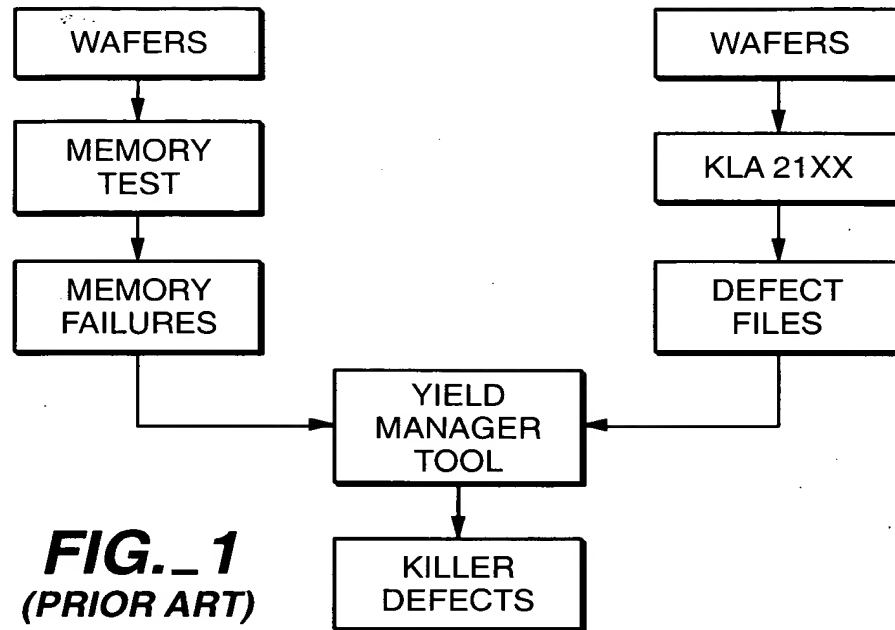


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APPROVED	Q.G. FIG.	
BY	CLASS	203CLASS
DRAFTSMAN	714	724

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```
DeviceID = DEMOID
LotID = TESTLOT01
WaferID = 01
DIE = -4,0
datalog.scan.10 diagnosis summary, #failing_patterns=9 #defects=2
#unexplained_fails=2
unexplained patterns = 212 250
-----
```

```
fault candidates for defect 1, #failing_patterns_explained=5
-----
```

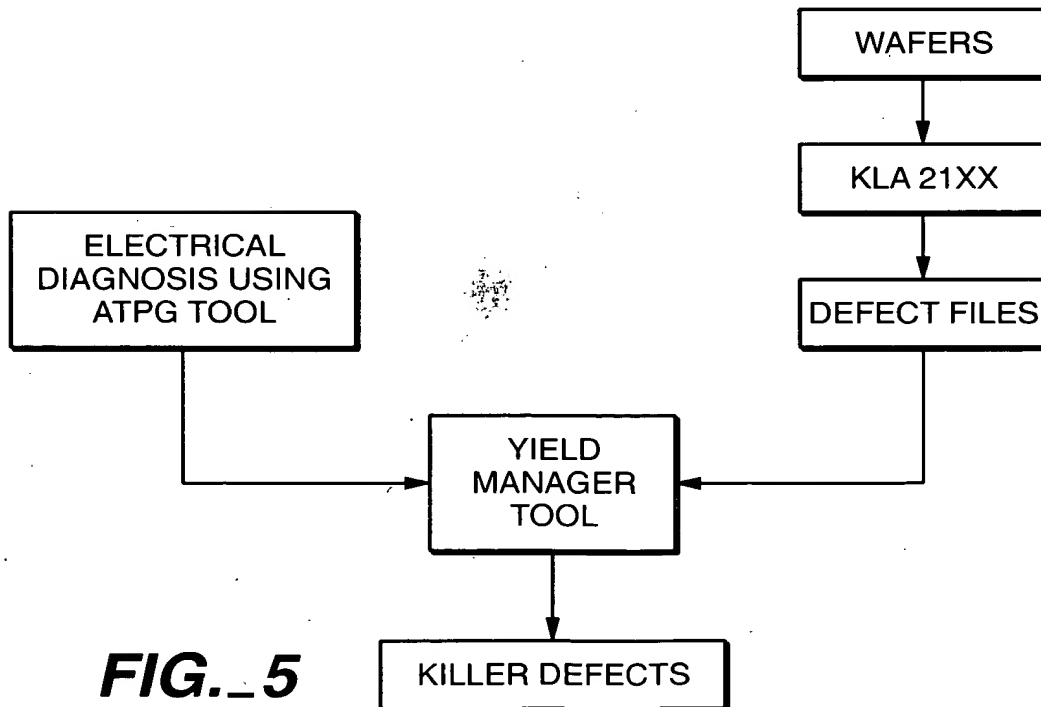
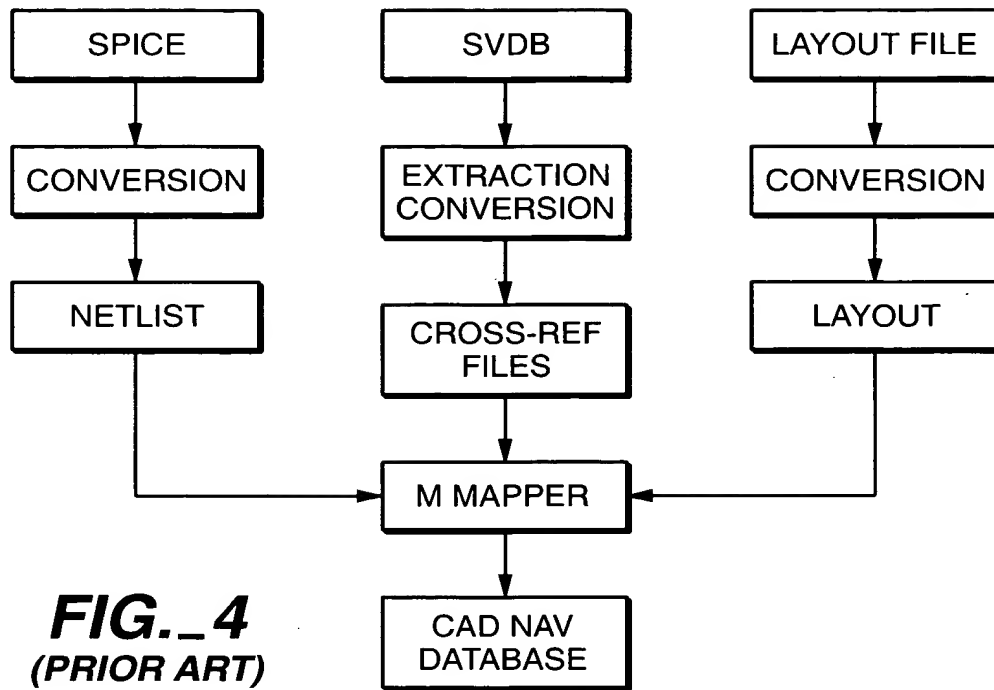
```
Warning: Fault candidates will cause passing patterns to fail.
failing patterns explained = 322 706 738 770
```

```
type code pin_pathname
-----
```

```
1 DS /XTIO_0/XTTLI8_1612/N2_23
1 DS /PI9
-----
```

```
diagnosis CPU time = .68 sec
-----
```

FIG.-3
(PRIOR ART)



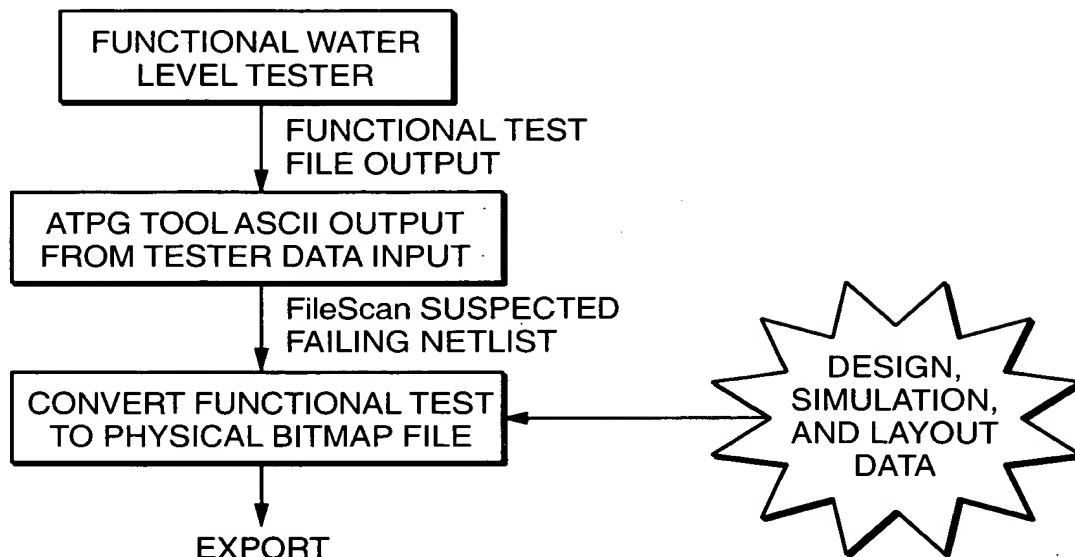
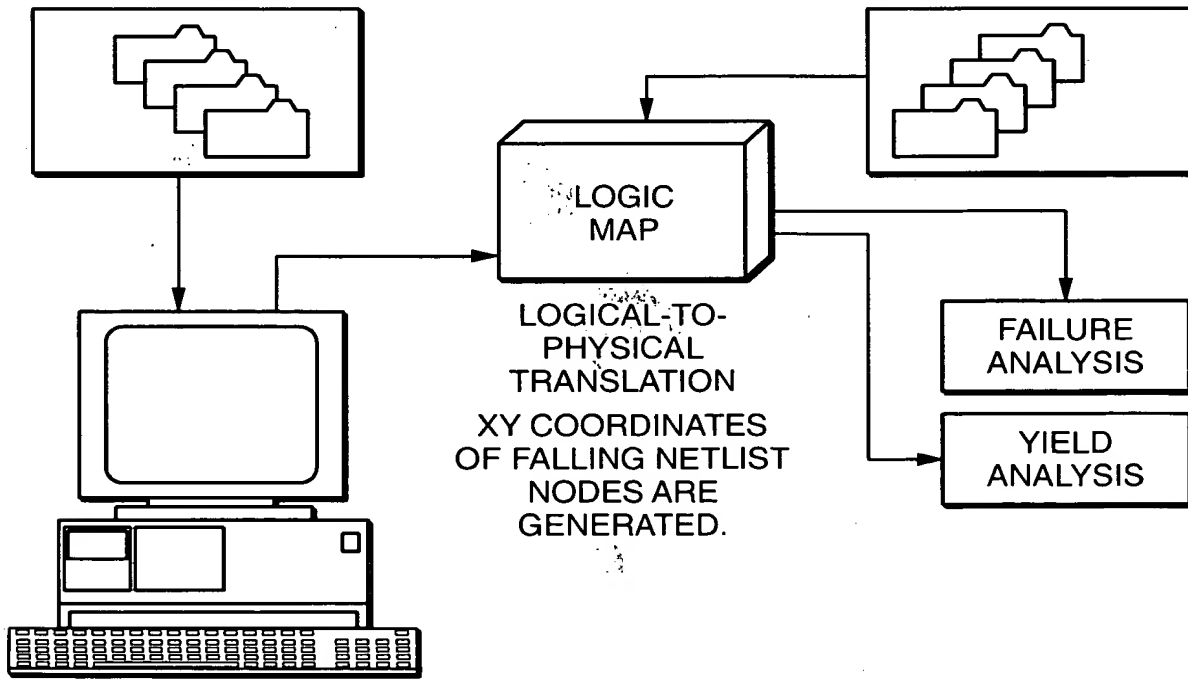


FIG._6

TESTER GENERATED FILES
TESTERS GENERATE
DATALOGS FOR EACH
DIE TESTED.

DESIGN DATA
LogicMap READS THE
GDSII FILE INPUT,
NETLIST AND LSV DATA.



FastScan UNIX SERVER
A FRACTION OF THE
DATALOGS ARE TRANSLATED
INTO FastScan FORMAT.

FIG._10

APPROVED	O.G. FIG.	
BY	CLASS	DATE
DRAFTSMAN	714	724

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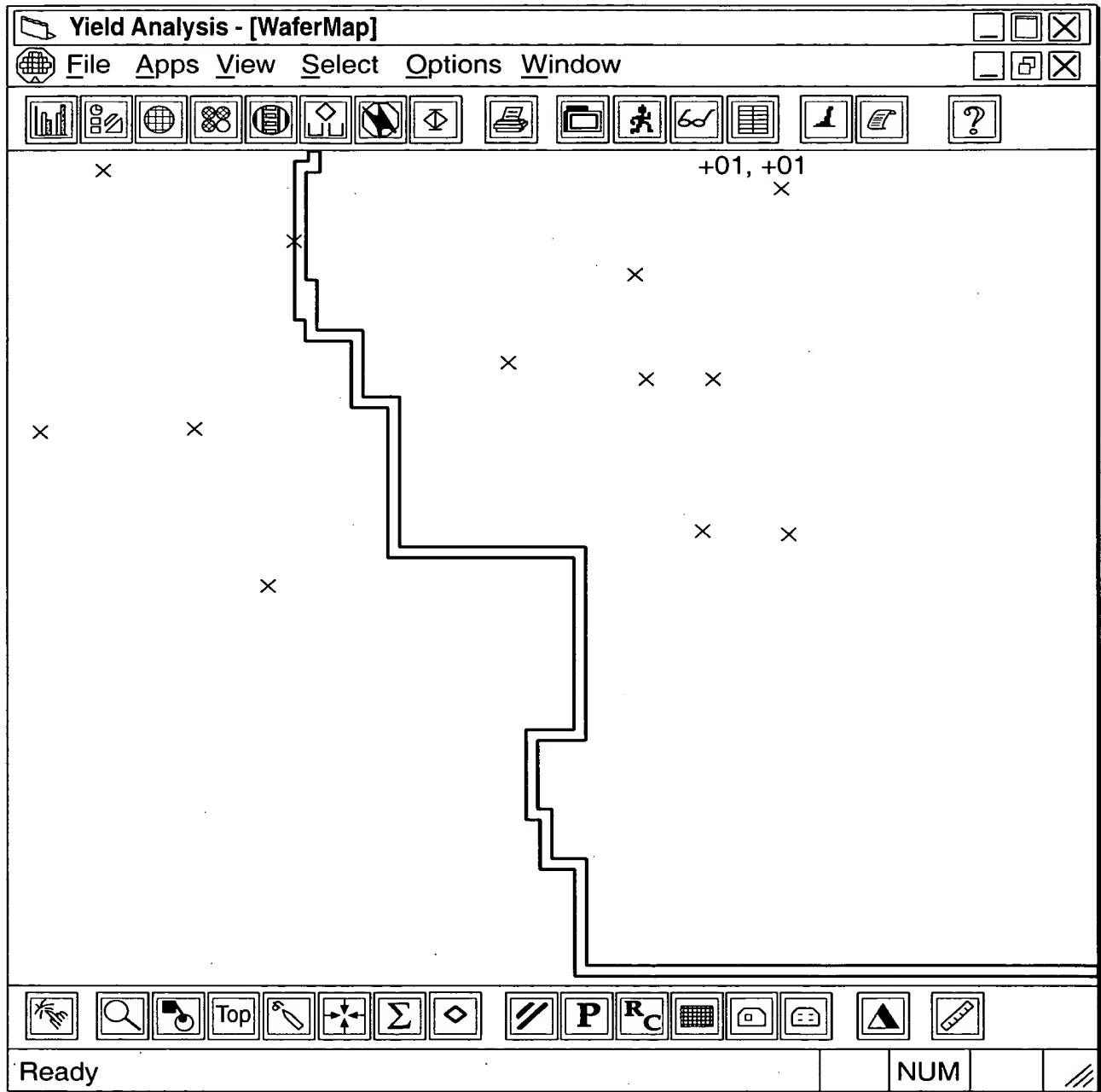


FIG._7

APPROVED	Q.G. FIG.	
BY	011829	BC16SS
DRAFTSMAN	714	724

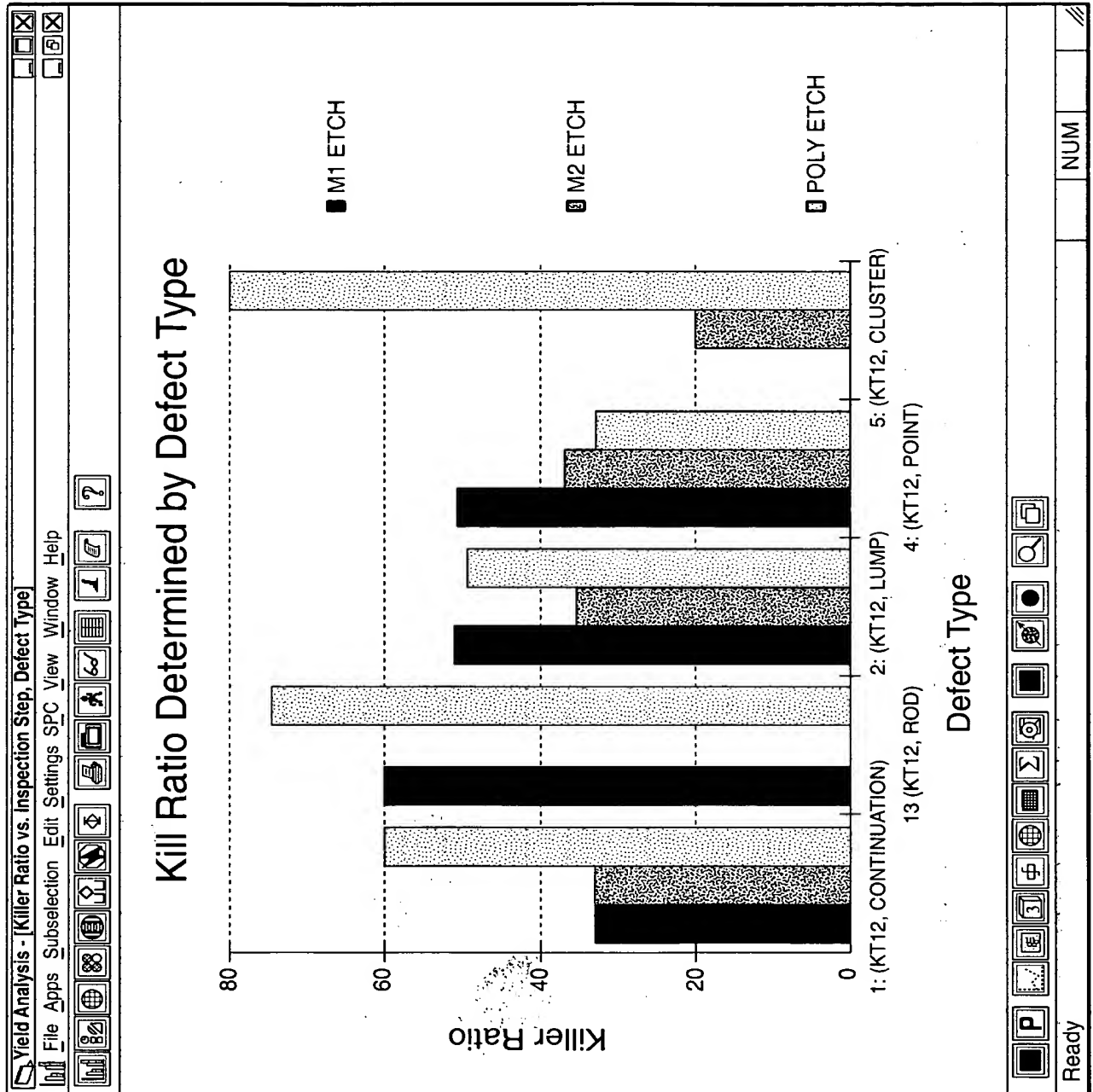


FIG.-8

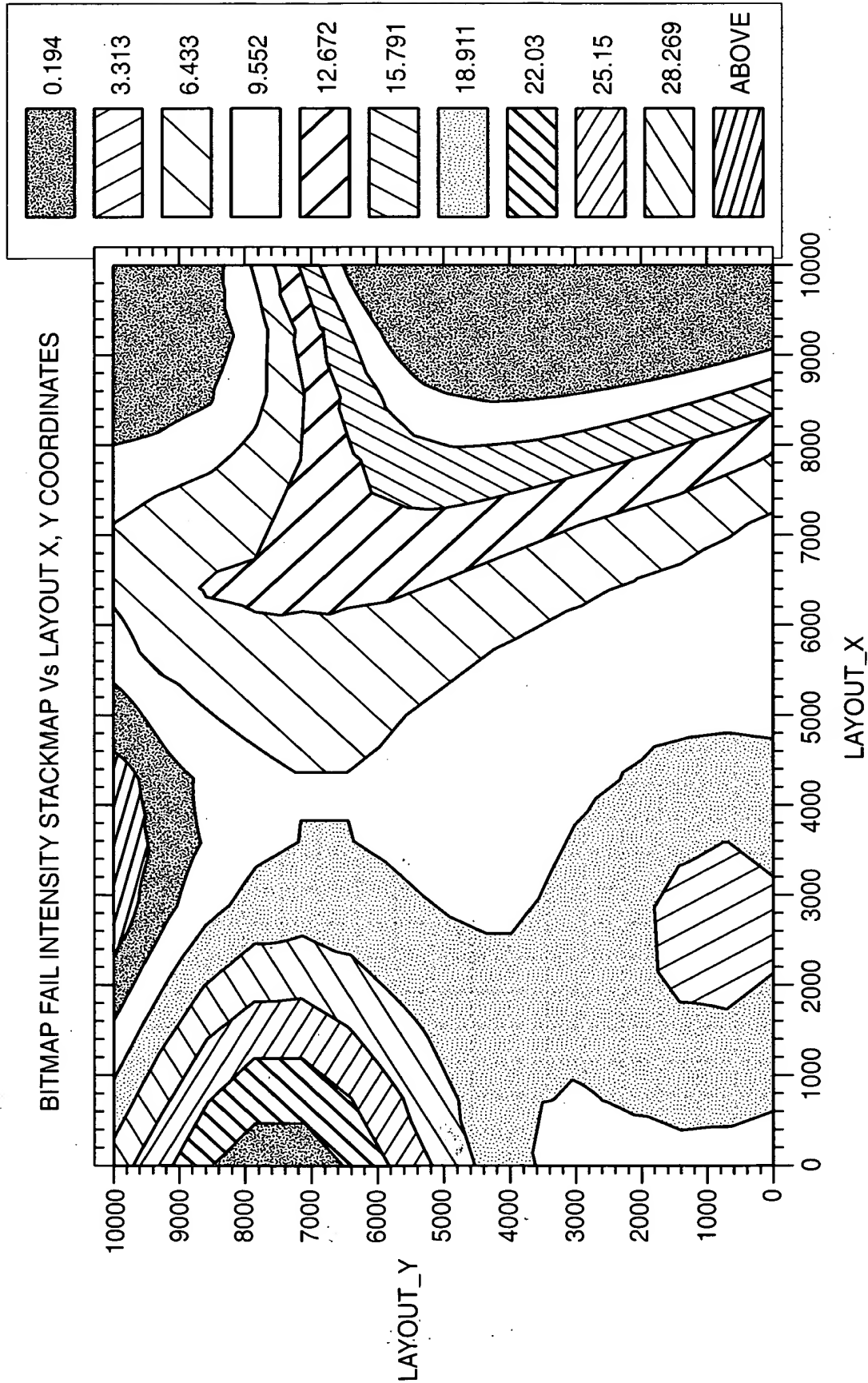


FIG.. 9

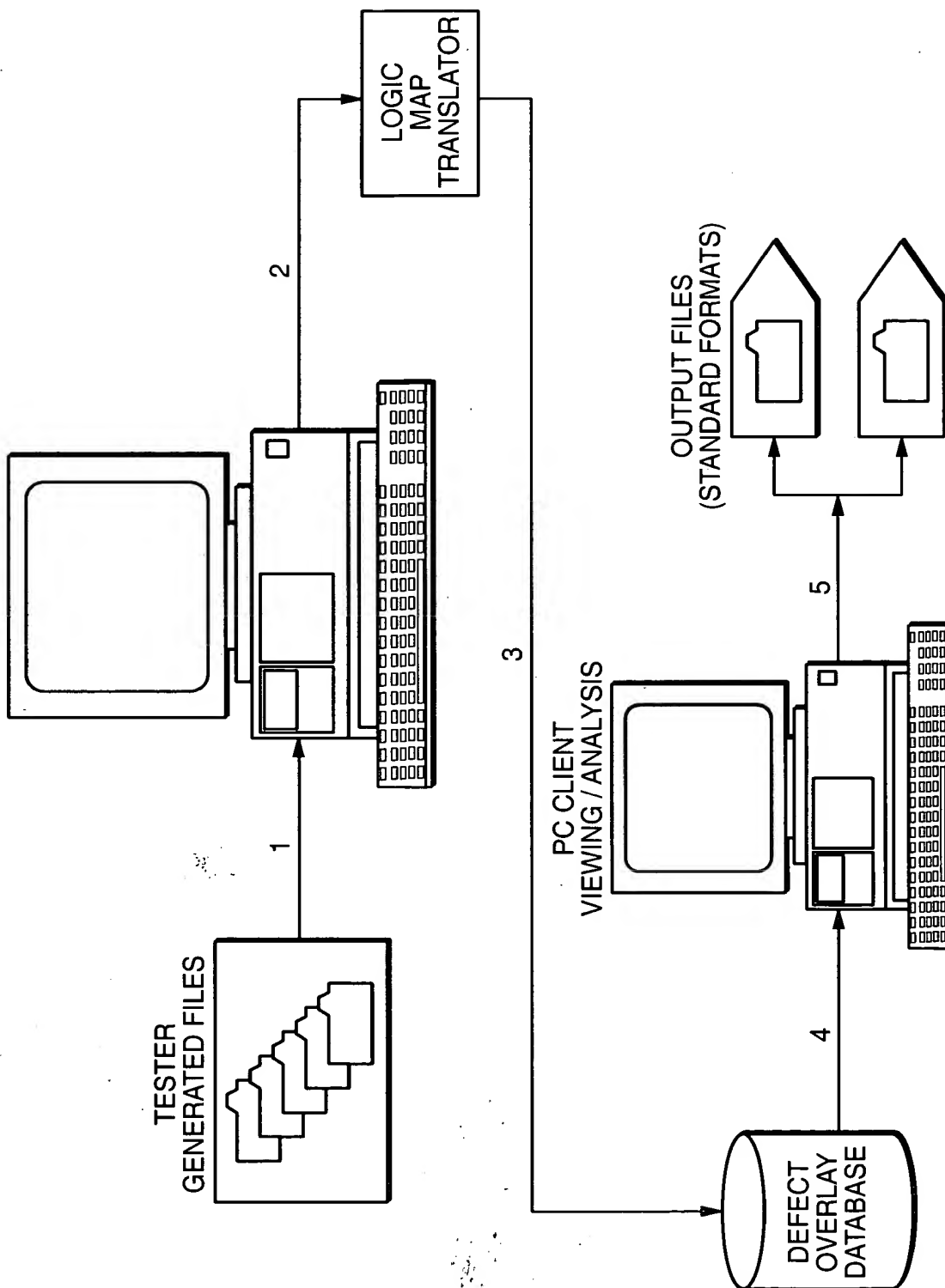


FIG..11

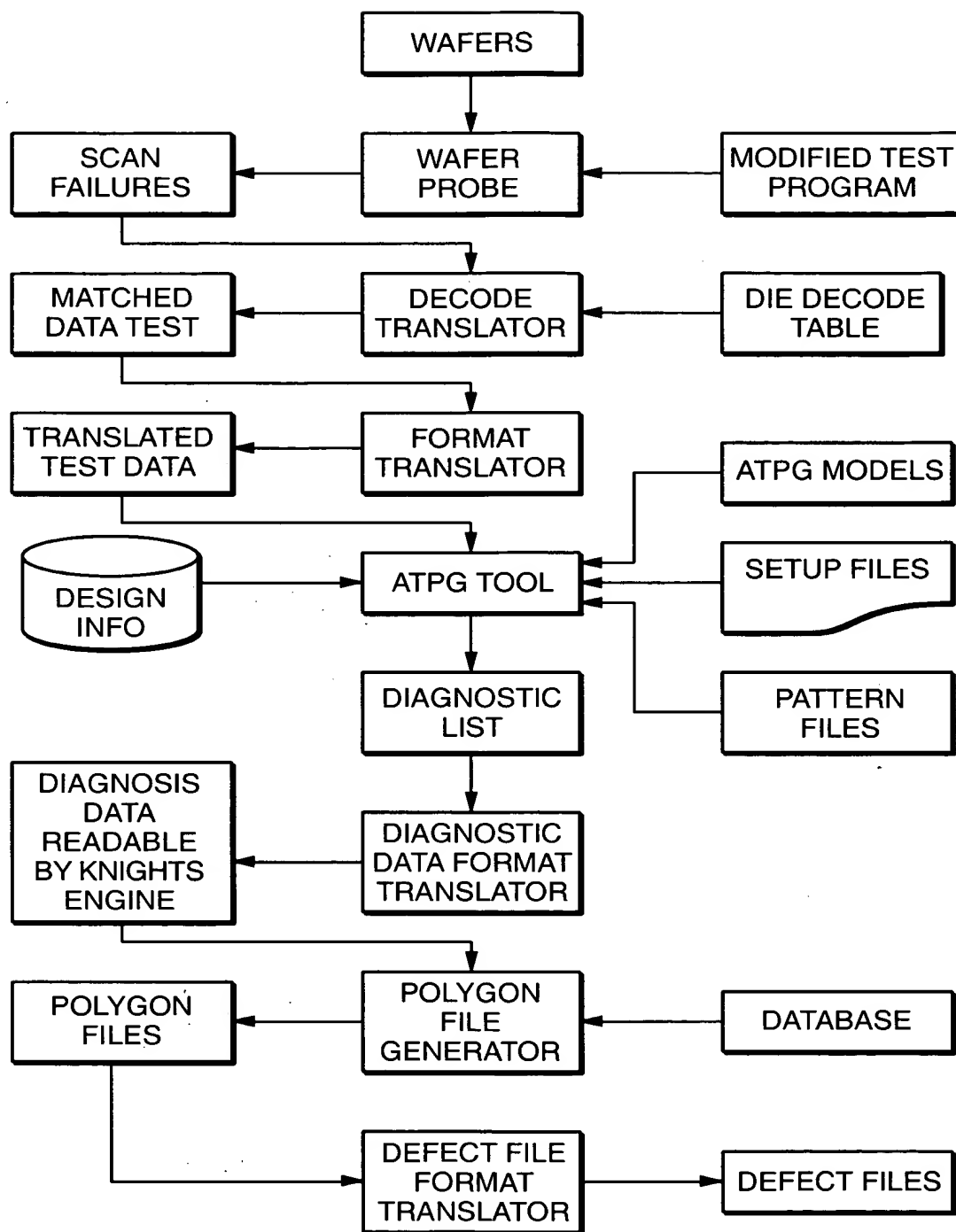


FIG. 12